

Notice of References Cited	Application/Control No. 10/734,598	Applicant(s)/Patent Under Reexamination HEINDTEL, MICHAEL	
	Examiner Vinod D. Patel	Art Unit 3742	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2,487,839	11-1949	ALEN DE WITT T VAN	338/218
	B	US-2,493,542	01-1950	MAX MCGRAW	338/319
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 01211884 A	08-1989	Japan	AKAGAWA, HIDEYUKI	H05B 03/20
	O	JP 04031576 A	02-1992	Japan	SAWAHARA et al.	E04H 09/16
	P	JP 03084423 A	04-1991	Japan	TAKAHASHI et al.	G01F 01/68
	Q	JP 07092852 A	04-1995	Japan	YUNAMOCHI et al.	G03G 15/20
	R	JP 05290953 A	11-1993	Japan	EGASHIRA, TSUTOMU	H05B 03/10
	S	JP 01281339 A	11-1989	Japan	IZUMIKAWA, MASAHIITO	F24D 13/02
	T	JP 04020721 A	01-1992	Japan	SHIBATA, KOKICHI	F24C 07/06

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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